CDE

ResMap 168-Solar

The ResMap Model 168-Solar was designed to meet the needs of photovoltaic and other solar cell manufacturing metrology -- delivering the reliability, accuracy and repeatability for which the ResMap is known. With its auto cassette load capability the Model 168-Solar increases throughput and lowers the cost of ownership of conductive material metrology.

Wafer handling:	Auto cassette load
Wafer Size:	Auto load & manual load: 125mm x 125mm 150mm x 150mm 156mm x 156mm 2" – 8" diameter
Max Square:	156mm x 156mm
Typical Measurement Time:	1 second per site
Typical Wafer Handling Time:	10 seconds each way
Maximum Throughput:	40 wph (49 sites); 80 wph (5 sites)
Measurement Range:	2 mΩ/□ - 5 MΩ/□ (can be optimized to 1 mΩ/□)
Repeatability (1σ, typical):	≤ ±0.02% (static or Rs pack); ≤ ±0.2% (dynamic nearby spots)
Accuracy:	≤ ±0.5% using NIST traceable ResCal standards
Minimum Edge Exclusion:	1.5mm (center of probe to edge of film)

Computer System:	Pentium class; Windows XP Home (display not included)
SECS-II Option:	Available
Mapping Patterns:	Square (or rectangular) map (choose inside edge exclusion); line scan (any point to point, minimum step 0.1mm); or user defined with template
Plots:	Contour (spacing choice, 1/3σ, fixed and auto %), 3D, line, data map, histogram, data sequence, radial and angular distributions; various modes of trend charts available
Data:	All ResMap data files may be ported to programs such as Excel® for further analysis.

Facilities	
House Vacuum :	Required; >500 mm Hg, on ¼" OD flexible tubing
AC Power:	100V to 240V < 10 KVA
Size (inches): width x depth x height	12" w x 28"d x 10"h; tabletop (table not included)